

Search Notes

Application/Control No.

10/757,095

Examiner

John J. Park

Applicant(s)/Patent under
Reexamination

ATTIA ET AL.

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	462.46		
235	462.25		
235	462.01		
235	462.07		
235	462.11		
235	383		
235	385		
382	289		
349	117		
455	422	2/18/2005	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST		
Text Search		
Consulted with S. Paik in AU 2876	2/18/2005	JP